

OptiMOS™ Power-MOSFET
Features

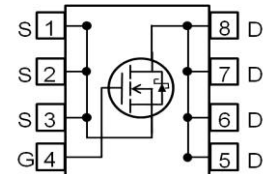
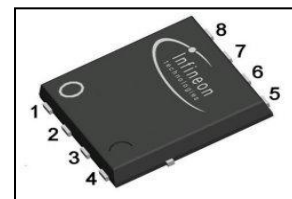
- Optimized for high performance Buck converter
- Monolithic integrated Schottky like diode
- Very low on-resistance $R_{DS(on)}$ @ $V_{GS}=4.5\text{ V}$
- 100% avalanche tested
- N-channel
- Qualified according to JEDEC¹⁾ for target applications
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21



| Type | Package | Marking |
|--------------|------------|----------|
| BSC014NE2LSI | PG-TDSON-8 | 014NE2LI |

Product Summary

| | | |
|------------------|-----|----|
| V_{DS} | 25 | V |
| $R_{DS(on),max}$ | 1.4 | mΩ |
| I_D | 100 | A |
| Q_{OSS} | 25 | nC |
| $Q_G(0V..10V)$ | 39 | nC |

PG-TDSON-8

Maximum ratings, at $T_j=25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|---|---------------|---|-------|------|
| Continuous drain current | I_D | $V_{GS}=10\text{ V}, T_C=25\text{ °C}$ | 100 | A |
| | | $V_{GS}=10\text{ V}, T_C=100\text{ °C}$ | 100 | |
| | | $V_{GS}=4.5\text{ V}, T_C=25\text{ °C}$ | 100 | |
| | | $V_{GS}=4.5\text{ V}, T_C=100\text{ °C}$ | 94 | |
| | | $V_{GS}=10\text{ V}, T_A=25\text{ °C}, R_{thJA}=50\text{ K/W}^2)$ | 33 | |
| Pulsed drain current ³⁾ | $I_{D,pulse}$ | $T_C=25\text{ °C}$ | 400 | |
| Avalanche current, single pulse ⁴⁾ | I_{AS} | $T_C=25\text{ °C}$ | 50 | |
| Avalanche energy, single pulse | E_{AS} | $I_D=50\text{ A}, R_{GS}=25\text{ Ω}$ | 50 | mJ |
| Gate source voltage | V_{GS} | | ±20 | V |

¹⁾ J-STD20 and JESD22

²⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

Maximum ratings, at $T_j=25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|-------------------------------------|-----------------------|--|-------------|------|
| Power dissipation | P_{tot} | $T_C=25\text{ °C}$ | 74 | W |
| | | $T_A=25\text{ °C}$, $R_{\text{thJA}}=50\text{ K/W}^2)$ | 2.5 | |
| Operating and storage temperature | T_j, T_{stg} | | -55 ... 150 | °C |
| IEC climatic category; DIN IEC 68-1 | | | 55/150/56 | |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Thermal characteristics

| | | | | | | |
|-------------------------------------|-------------------|--|---|---|-----|-----|
| Thermal resistance, junction - case | R_{thJC} | | - | - | 1.7 | K/W |
| | | top | - | - | 20 | |
| Device on PCB | R_{thJA} | 6 cm ² cooling area ²⁾ | - | - | 50 | |

Electrical characteristics, at $T_j=25\text{ °C}$, unless otherwise specified

Static characteristics

| | | | | | | |
|---|---|---|-----|-----|-----|------|
| Drain-source breakdown voltage | $V_{(\text{BR})\text{DSS}}$ | $V_{\text{GS}}=0\text{ V}, I_{\text{D}}=10\text{ mA}$ | 25 | - | - | V |
| Breakdown voltage temperature coefficient | $\frac{dV_{(\text{BR})\text{DSS}}}{dT_j}$ | $I_{\text{D}}=10\text{ mA}$, referenced to 25 °C | - | 15 | - | mV/K |
| Gate threshold voltage | $V_{\text{GS(th)}}$ | $V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\text{ }\mu\text{A}$ | 1.2 | - | 2.0 | V |
| Zero gate voltage drain current | I_{DSS} | $V_{\text{DS}}=20\text{ V}, V_{\text{GS}}=0\text{ V}, T_j=25\text{ °C}$ | - | - | 0.5 | mA |
| | | $V_{\text{DS}}=20\text{ V}, V_{\text{GS}}=0\text{ V}, T_j=125\text{ °C}$ | - | 2 | - | |
| Gate-source leakage current | I_{GSS} | $V_{\text{GS}}=20\text{ V}, V_{\text{DS}}=0\text{ V}$ | - | 10 | 100 | nA |
| Drain-source on-state resistance | $R_{\text{DS(on)}}$ | $V_{\text{GS}}=4.5\text{ V}, I_{\text{D}}=30\text{ A}$ | - | 1.6 | 2 | mΩ |
| | | $V_{\text{GS}}=10\text{ V}, I_{\text{D}}=30\text{ A}$ | - | 1.2 | 1.4 | |
| Gate resistance | R_{G} | | 0.3 | 0.6 | 1.2 | Ω |
| Transconductance | g_{fs} | $ V_{\text{DS}} >2 I_{\text{D}} R_{\text{DS(on)max}}, I_{\text{D}}=30\text{ A}$ | 70 | 140 | - | S |

³⁾ See figure 3 for more detailed information

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Dynamic characteristics

| | | | | | | |
|------------------------------|--------------|--|---|------|------|----|
| Input capacitance | C_{iss} | $V_{GS}=0\text{ V}, V_{DS}=12\text{ V}, f=1\text{ MHz}$ | - | 2700 | 3591 | pF |
| Output capacitance | C_{oss} | | - | 1200 | 1596 | |
| Reverse transfer capacitance | C_{rss} | | - | 120 | - | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=12\text{ V}, V_{GS}=10\text{ V}, I_D=30\text{ A}, R_{G,ext}=1.6\ \Omega$ | - | 5.0 | - | ns |
| Rise time | t_r | | - | 5.0 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 25 | - | |
| Fall time | t_f | | - | 3.6 | - | |

Gate Charge Characteristics⁵⁾

| | | | | | | |
|------------------------------|---------------|--|---|------|----|----|
| Gate to source charge | Q_{gs} | $V_{DD}=12\text{ V}, I_D=30\text{ A}, V_{GS}=0\text{ to }4.5\text{ V}$ | - | 6.8 | 9 | nC |
| Gate charge at threshold | $Q_{g(th)}$ | | - | 4.4 | - | |
| Gate to drain charge | Q_{gd} | | - | 4.7 | 7 | |
| Switching charge | Q_{sw} | | - | 7 | - | |
| Gate charge total | Q_g | | - | 18.7 | 25 | |
| Gate plateau voltage | $V_{plateau}$ | | - | 2.5 | - | V |
| Gate charge total | Q_g | $V_{DD}=12\text{ V}, I_D=30\text{ A}, V_{GS}=0\text{ to }10\text{ V}$ | - | 39 | 52 | nC |
| Gate charge total, sync. FET | $Q_{g(sync)}$ | $V_{DS}=0.1\text{ V}, V_{GS}=0\text{ to }4.5\text{ V}$ | - | 16 | - | |
| Output charge | Q_{oss} | $V_{DD}=12\text{ V}, V_{GS}=0\text{ V}$ | - | 25 | 33 | |

Reverse Diode

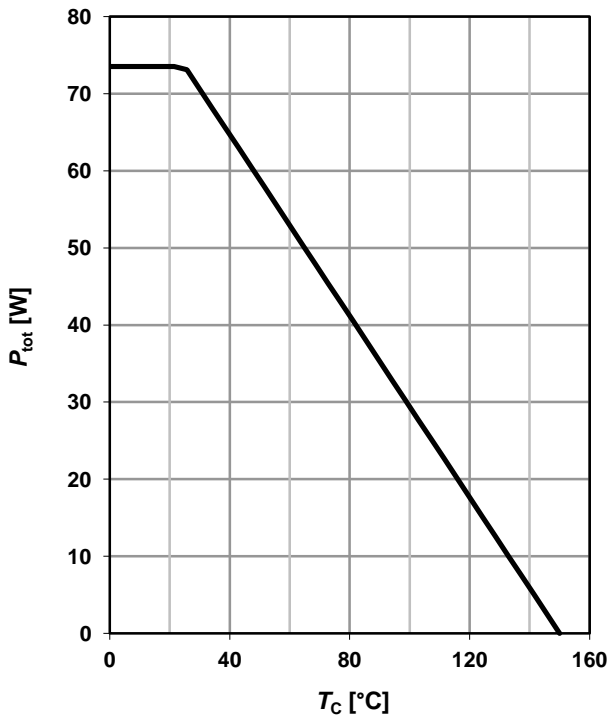
| | | | | | | |
|----------------------------------|---------------|---|---|------|-----|----|
| Diode continuous forward current | I_S | $T_C=25\text{ }^\circ\text{C}$ | - | - | 74 | A |
| Diode pulse current | $I_{S,pulse}$ | | - | - | 296 | |
| Diode forward voltage | V_{SD} | $V_{GS}=0\text{ V}, I_F=8\text{ A}, T_j=25\text{ }^\circ\text{C}$ | - | 0.56 | - | V |
| Reverse recovery charge | Q_{rr} | $V_R=15\text{ V}, I_F=8\text{ A}, di_F/dt=400\text{ A}/\mu\text{s}$ | - | 5 | - | nC |

⁴⁾ See figure 13 for more detailed information

⁵⁾ See figure 16 for gate charge parameter definition

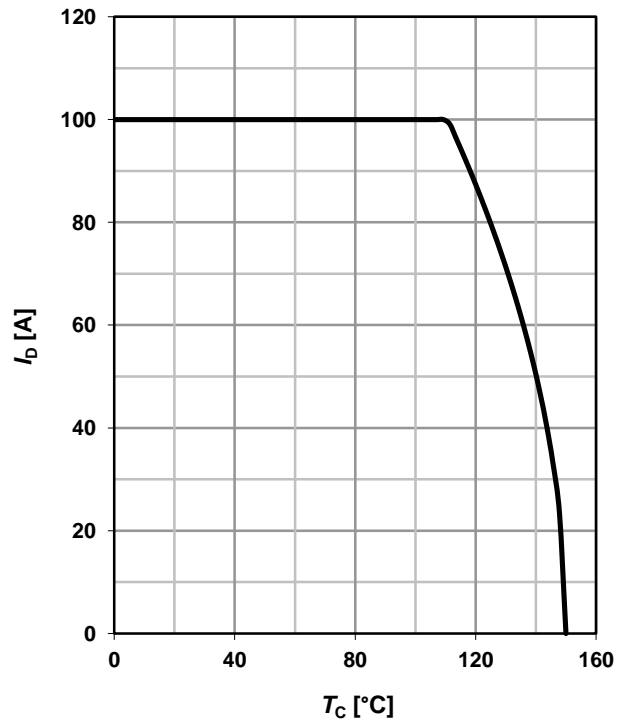
1 Power dissipation

$P_{tot}=f(T_C)$



2 Drain current

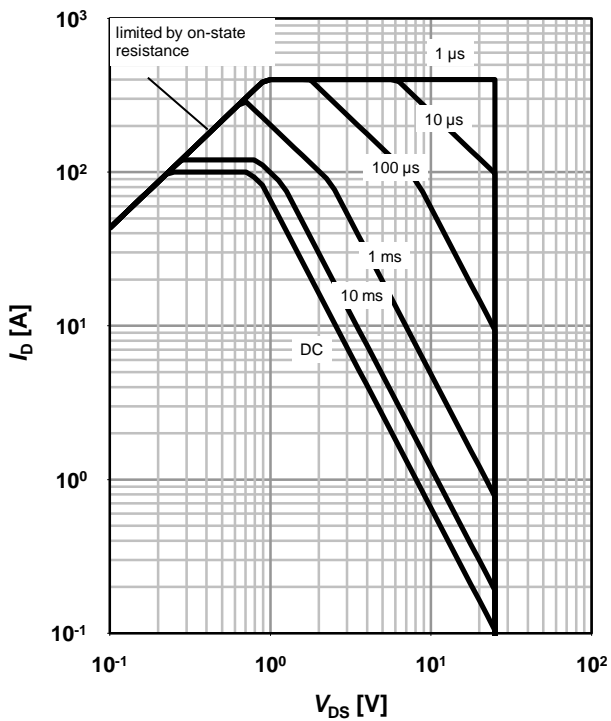
$I_D=f(T_C); V_{GS} \geq 10\text{ V}$



3 Safe operating area

$I_D=f(V_{DS}); T_C=25\text{ °C}; D=0$

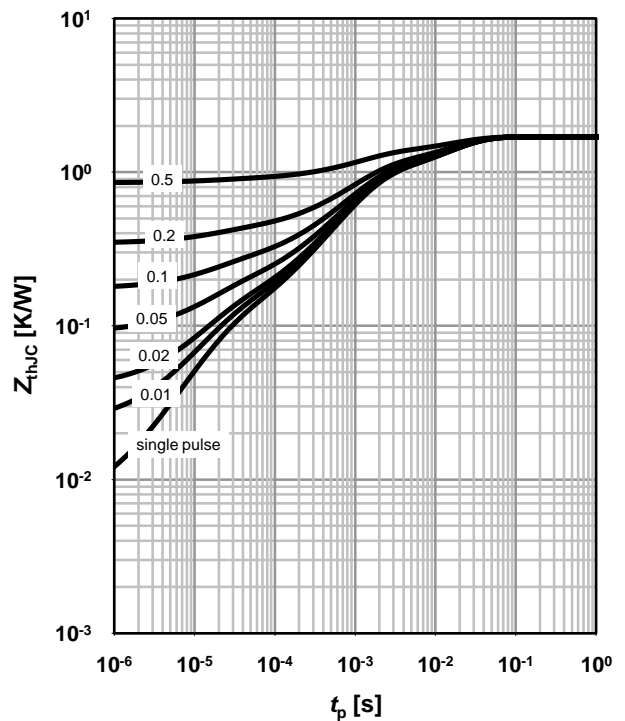
parameter: t_p



4 Max. transient thermal impedance

$Z_{thJC}=f(t_p)$

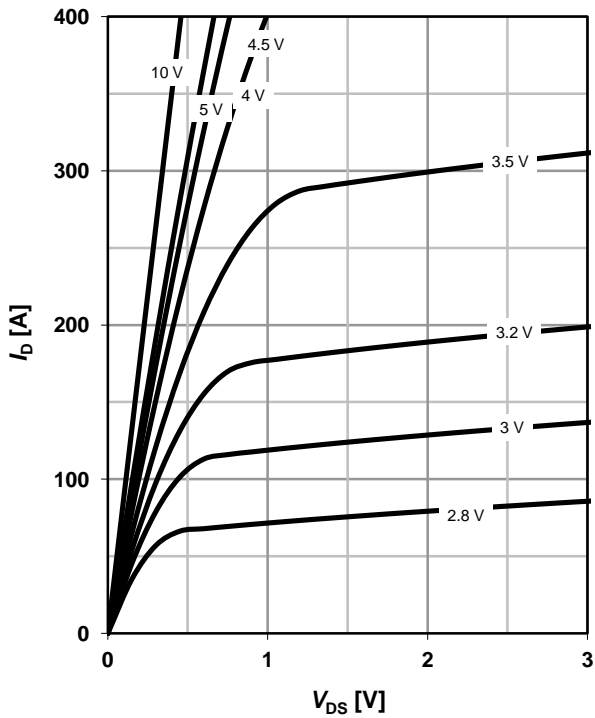
parameter: $D=t_p/T$



5 Typ. output characteristics

$I_D=f(V_{DS}); T_j=25\text{ }^\circ\text{C}$

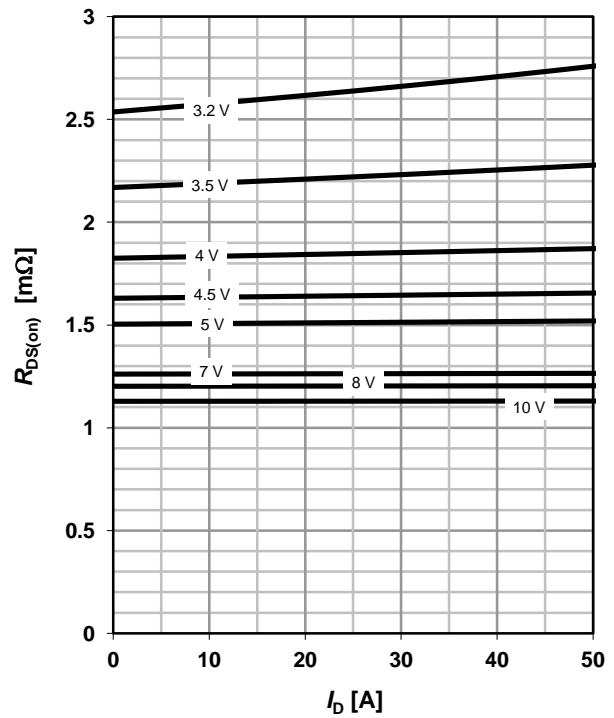
parameter: V_{GS}



6 Typ. drain-source on resistance

$R_{DS(on)}=f(I_D); T_j=25\text{ }^\circ\text{C}$

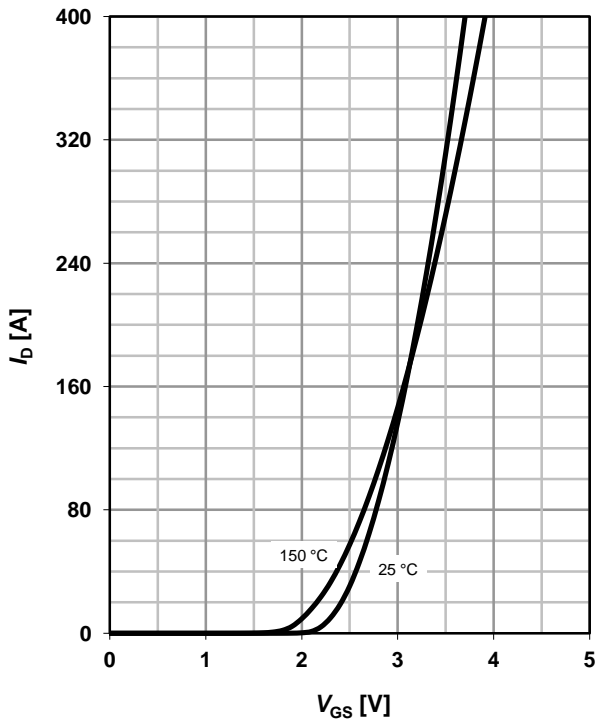
parameter: V_{GS}



7 Typ. transfer characteristics

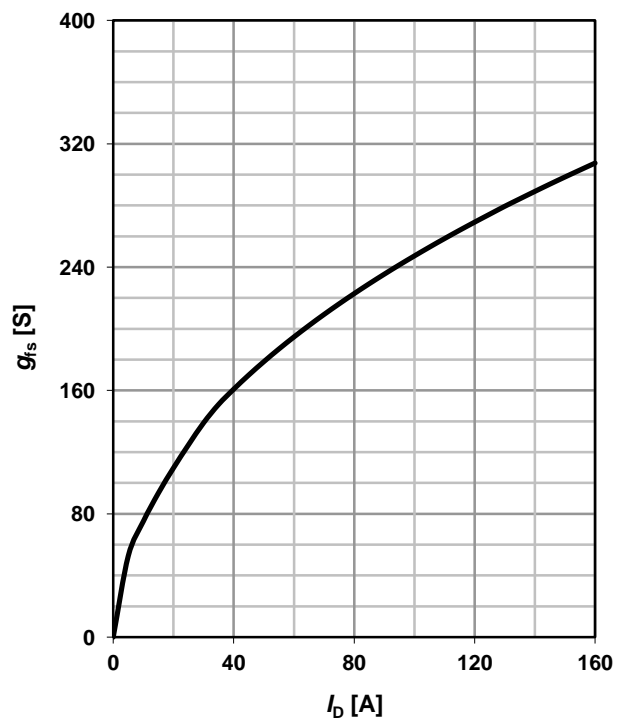
$I_D=f(V_{GS}); |V_{DS}|>2|I_D|R_{DS(on)max}$

parameter: T_j



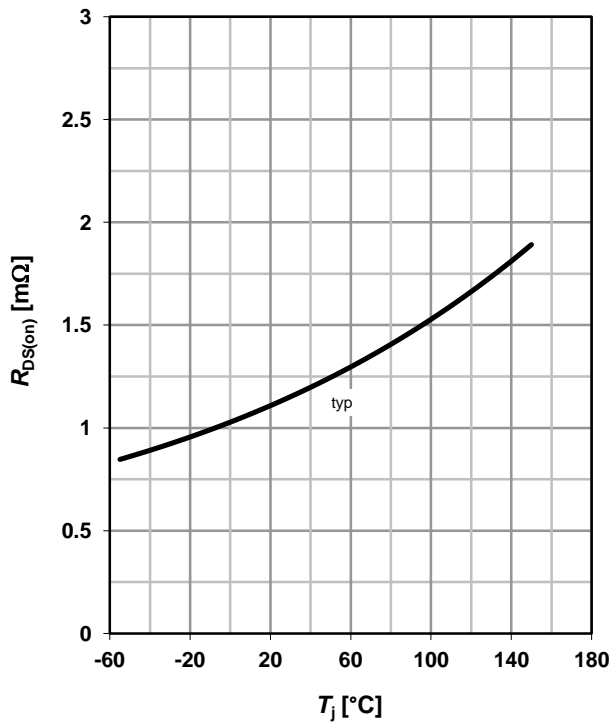
8 Typ. forward transconductance

$g_{fs}=f(I_D); T_j=25\text{ }^\circ\text{C}$



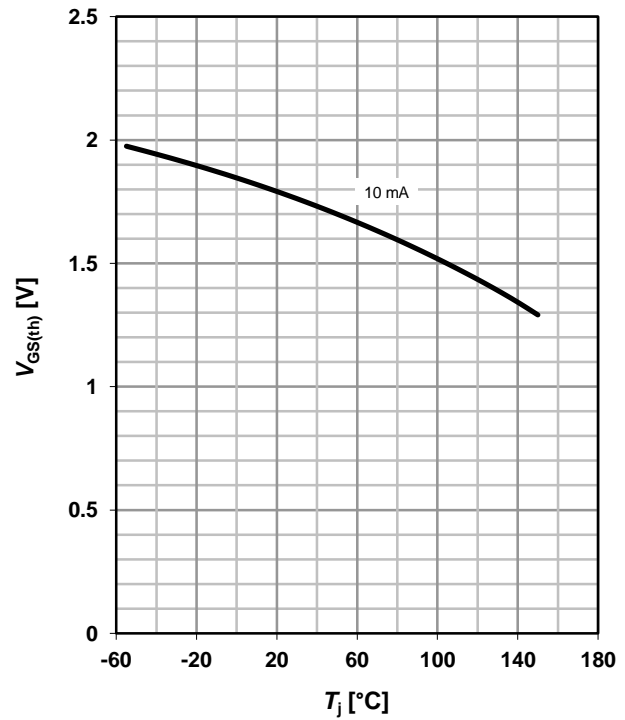
9 Drain-source on-state resistance

$R_{DS(on)}=f(T_j); I_D=30\text{ A}; V_{GS}=10\text{ V}$



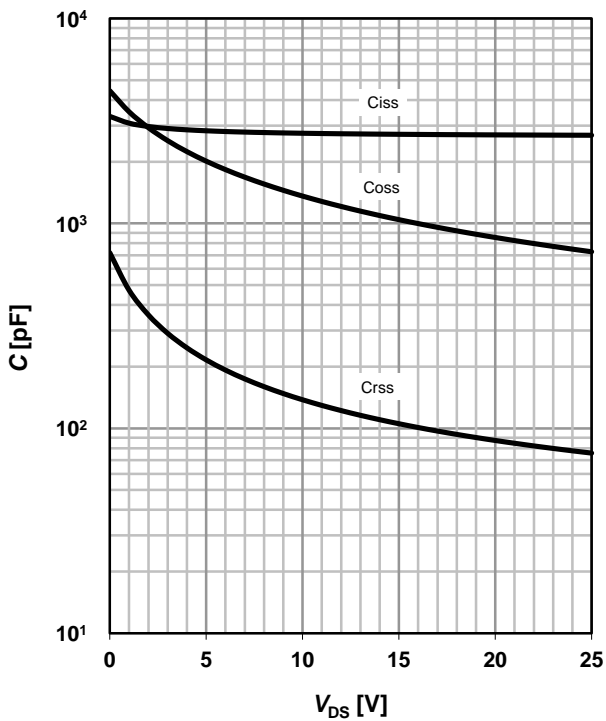
10 Typ. gate threshold voltage

$V_{GS(th)}=f(T_j); V_{GS}=V_{DS}; I_D=10\text{ mA}$



11 Typ. capacitances

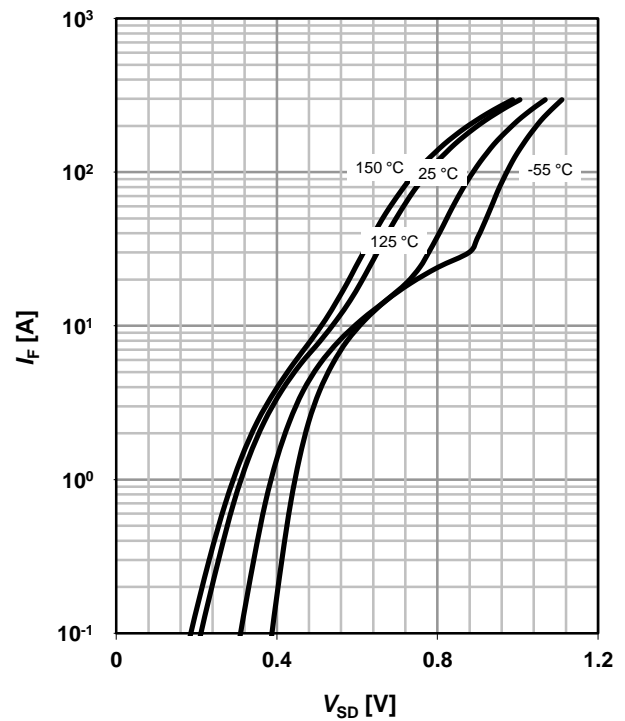
$C=f(V_{DS}); V_{GS}=0\text{ V}; f=1\text{ MHz}$



12 Forward characteristics of reverse diode

$I_F=f(V_{SD})$

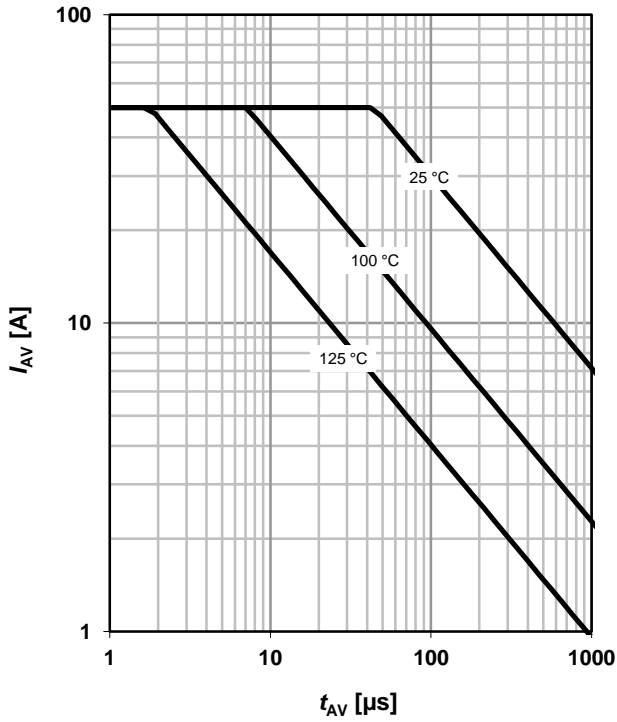
parameter: T_j



13 Avalanche characteristics

$I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$

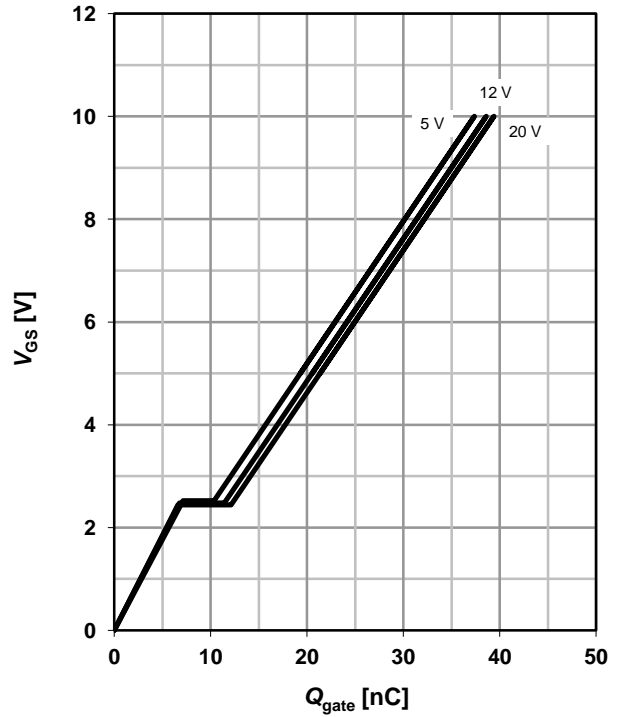
parameter: $T_{j(start)}$



14 Typ. gate charge

$V_{GS}=f(Q_{gate}); I_D=30 \text{ A pulsed}$

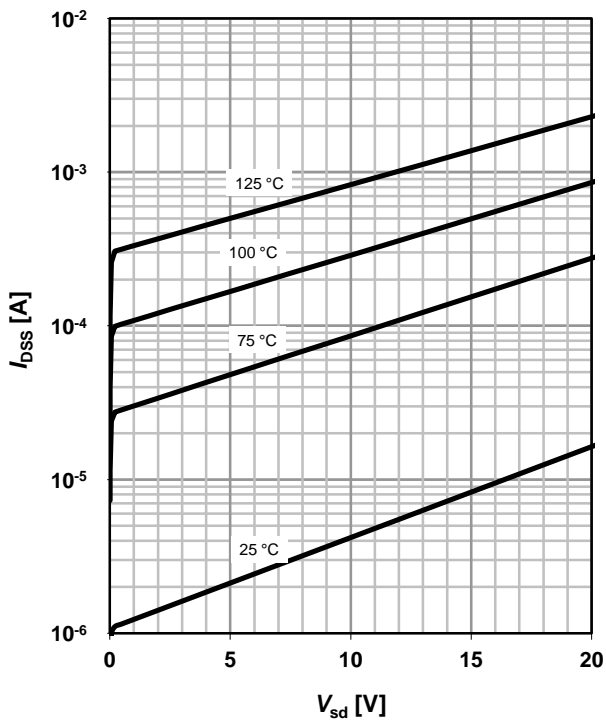
parameter: V_{DD}



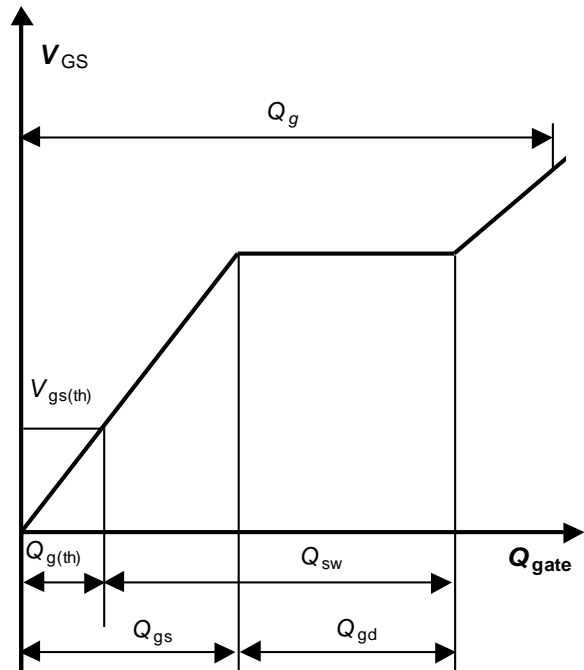
15 Typ. drain-source leakage current

$I_{DSS}=f(V_{DS}); V_{GS}=0 \text{ V}$

parameter: T_j



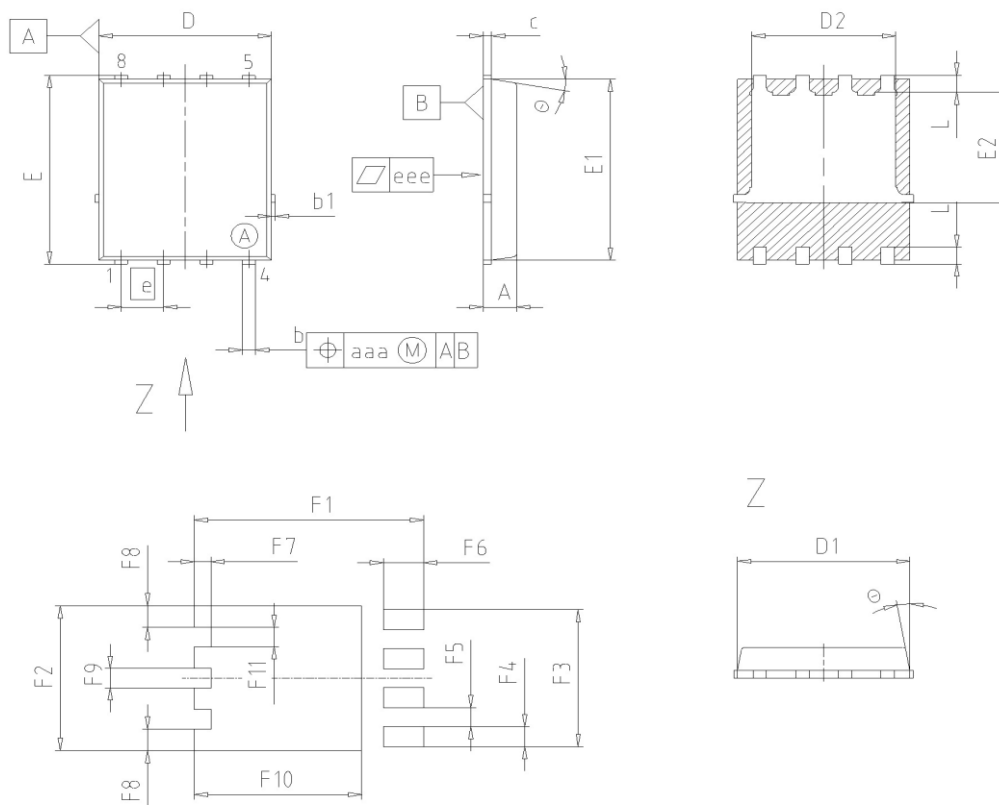
16 Gate charge waveforms



Package Outline

PG-TDSON-8

PG-TDSON-8: Outline



| DIM | MILLIMETERS | | INCHES | |
|------|-------------|-------|--------|-------|
| | MIN | MAX | MIN | MAX |
| A | 0.90 | 1.10 | 0.035 | 0.043 |
| b | 0.34 | 0.54 | 0.013 | 0.021 |
| b1 | 0.02 | 0.22 | 0.001 | 0.008 |
| c | 0.15 | 0.35 | 0.006 | 0.014 |
| D=D1 | 4.95 | 5.35 | 0.195 | 0.211 |
| D2 | 4.20 | 4.40 | 0.165 | 0.173 |
| E | 5.95 | 6.35 | 0.234 | 0.250 |
| E1 | 5.70 | 6.10 | 0.224 | 0.240 |
| E2 | 3.40 | 3.80 | 0.134 | 0.150 |
| e | 1.27 | | 0.050 | |
| N | 8 | | 8 | |
| L | 0.45 | 0.65 | 0.018 | 0.026 |
| □ | 8.5° | 11.5° | 8.5° | 11.5° |
| aaa | 0.25 | | 0.010 | |
| eee | 0.05 | | 0.002 | |
| F1 | 6.75 | 6.95 | 0.266 | 0.274 |
| F2 | 4.60 | 4.80 | 0.181 | 0.189 |
| F3 | 4.36 | 4.56 | 0.172 | 0.180 |
| F4 | 0.55 | 0.75 | 0.022 | 0.030 |
| F5 | 0.52 | 0.72 | 0.020 | 0.028 |
| F6 | 1.10 | 1.30 | 0.043 | 0.051 |
| F7 | 0.40 | 0.60 | 0.016 | 0.024 |
| F8 | 0.60 | 0.80 | 0.024 | 0.031 |
| F9 | 0.53 | 0.73 | 0.021 | 0.029 |
| F10 | 4.90 | 5.10 | 0.193 | 0.201 |
| F11 | 0.53 | 0.73 | 0.021 | 0.029 |

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